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AP20 RECEIVED 20 APR 2006 10576453 - GAU: 4118 Sheet 1 of 1

FORM PTO-1449 (REV. 7-80)	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY DOCKET NO. <b>10/1870253</b> <b>5005.1107</b>	APPLICATION NO. <b>3</b> To be assigned
<b>LIST OF PRIOR ART CITED BY APPLICANT</b>  (Use several sheets if necessary)		APPLICANT <b>Frank SIECKMANN et al.</b>	
		FILING DATE <b>Herewith</b>	GROUP <b>3742</b> <del>To be assigned</del>

**U.S. PATENT DOCUMENTS**

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	A01	4,741,043	Apr. 26, 1988	Bacus	382	6
	A02	5,843,657	Dec. 1, 1998	Liotta et al.	435	6
	A03	5,998,129	Dec. 7, 1999	Schütze et al.	435	4
	A04	2002/0090122	Jul. 11, 2002	Baer et al.	382	128
	A05	2002/0164678	Nov. 7, 2002	Ganser et al.	435	40.5
	A06	6,787,301	Sep. 7, 2004	Ganser et al.	435	4
	A07	6,907,798	Jun. 21, 2005	Ganser et al.	73	864.41
	A08	5,031,099	Jul. 9, 1991	Kettler	364	413.08
	A09	5,843,644	Dec. 1, 1998	Liotta et al.	435	6
	A10	6,713,264	Mar. 30, 2004	Luttermann et al.	435	7.1
	A11	6,991,714	Jan. 31, 2006	Gauss et al.	204	462

**FOREIGN PATENT DOCUMENTS**

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION
					YES      NO
A12	WO 01/73398	Oct. 4, 2001	WO-WIPO		See Abstract
A13	DE 100 18 251	Oct. 25, 2001	DE-Germany		Corresponds to US 6,907,798
A14	DE 100 43 506	Dec. 6, 2001	DE-Germany		Corresponds to US 6,787,301
A15	DE 196 36 074	Mar. 26, 1998	DE-Germany		See Intl. Search Report for PCT/EP2004/052600; see English Abstract
A16	DE 695 10 925	Feb. 17, 2000	DE-Germany		Corresponds to US 5,843,644
A17	DE 42 11 904	Nov. 19, 1992	DE-Germany		See Abstract
A18	DE 196 29 141	Apr. 16, 1998	DE-Germany		Corresponds to US 6,713,264
A19	DE 38 36 716	May 3, 1990	DE-Germany		Corresponds to US 5,031,099
A20	DE 198 15 400	Oct. 14, 1999	DE-Germany		Corresponds to US 6,991,714

<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)</b>	
A21	International Search Report for PCT/EP2004/052600 (4 pages)
A22	P.A.L.M. Microlaser Technologies: "PALM MicroBeam IP-MS + Metafer P, February 2003 (4 pages)
A23	ARCTURUS: "Laser Capture Microdissection (LCM) Systems", XP-002315059 (6 pages)
A24	B. J. SCHACHTER et al.: "Some Experiments in Image Segmentation by Clustering of Local Feature Values", XP-002269476, Pattern Recognition, Vol. 11, Pattern Recognition Society, Pergamon Press Ltd., Great Britain, pp.19-28
EXAMINER      /Hung Nguyen/	DATE CONSIDERED      08/11/2009
<small>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>	

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /H.N./